



**UNIVERSITI TUN HUSSEIN ONN MALAYSIA**

**FINAL EXAMINATION  
SEMESTER I  
SESSION 2022/2023**

COURSE NAME : ADVANCED SEMICONDUCTOR DEVICES

COURSE CODE : BEJ 43303

PROGRAMME CODE : BEJ

EXAMINATION DATE : FEBRUARY 2023

DURATION : 3 HOURS

INSTRUCTION : 1. ANSWER ALL QUESTIONS  
2. THIS FINAL EXAMINATION IS CONDUCTED VIA **CLOSED BOOK**  
3. STUDENTS ARE PROHIBITED TO CONSULT THEIR OWN MATERIAL OR ANY EXTERNAL RESOURCES DURING THE EXAMINATION CONDUCTED VIA CLOSED BOOK

THIS QUESTION PAPER CONSISTS OF **TEN (10)** PAGES

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**CONFIDENTIAL**

- Q1** (a) Consider a silicon *npn* BJT with the following parameters:

$$V_{BE} = 0.1 \text{ V}, A_{BE} = 5 \times 10^{-5} \text{ cm}^2, n_{B0} = 10^4 \text{ cm}^{-3}, x_B = 0.2 \text{ } \mu\text{m}, T = 300 \text{ K}$$

Determine the total minority carrier in base region at  $x = 0.05 \text{ } \mu\text{m}$ .

(7 marks)

- (b) Analyse **ONE (1)** significant effect of holes injection from base to emitter region on common-base current gain in BJT.

(5 marks)

- (c) Calculate the pinch-off current ( $I_p$ ) and pinch-off voltage ( $V_p$ ) of a silicon MESFET with given parameters:

$$N_a = 3 \times 10^{13} \text{ cm}^{-3}, N_d = 5 \times 10^{16} \text{ cm}^{-3}, a = 2 \times 10^3 \text{ } \text{Å}, \frac{Z}{L} = 1.5, T = 300 \text{ K}$$

(6 marks)

- (d) Using the answer obtained in part **Q1(c)**, calculate saturated drain current ( $I_{Dsat}$ ) of the transistor. Given  $\phi_{Bn} = 0.45 \text{ V}$  and  $V_G = 0 \text{ V}$ .

(7 marks)

- Q2** (a) Given the parameters of a silicon *n*-type DG MOSFET operating in sub-threshold region at  $T = 300 \text{ K}$  as follows:

$$t_{Si} = 750 \text{ } \text{Å}, V_D = 0.8 \text{ V}, V_G = 0.4 \text{ V}, \frac{W}{L} = 1.8$$

Calculate the drain current ( $I_D$ ) and transconductance ( $g_m$ ) of this transistor.

(7 marks)

- (b) Analyse **ONE (1)** possible factor that contributes to higher on-current in shorted gate FinFET compared to independent gate FinFET.

(5 marks)

- (c) Consider a silicon BJT which has the following parameters:

$$N_B = 10^{16} \text{ cm}^{-3}, x_{dB} = 0.5 \text{ } \mu\text{m}, V_{pt} = 25, T = 300 \text{ K}$$

Determine the required doping concentration for collector region ( $N_C$ ) for this device.

(7 marks)

- (d) Suppose a silicon JFET operates due to velocity saturation effect has the following parameters:

$$v_{sat} = 3 \times 10^5 \text{ cm/s}, N_d = 2 \times 10^{16} \text{ cm}^{-3}, W = 9.2 \text{ } \mu\text{m}, a = 6h_{sat} = 18 \text{ } \mu\text{m}$$

Determine the drain current ( $I'_{Dsat}$ ) of this transistor.

(6 marks)

- Q3 (a) Consider a silicon pin diode with the following parameters:

$$V_{BD} = 25 \text{ V}, E_m = 2.5 \times 10^5 \text{ V/cm}, \Delta n = 10^{15} \text{ cm}^{-3}, \\ A = 5 \times 10^{-5} \text{ cm}^2, v_s = 10^5 \text{ cm/s}$$

Determine the RF resistance ( $R_{RF}$ ) and forward current density ( $J_F$ ) of this diode. (6 marks)

- (b) Calculate the doping concentration in n-layer ( $N_1$ ) and maximum current density ( $J_m$ ) of a silicon Read diode that has the following parameters:

$$V_B = 10^2 \text{ V}, W_D = 8b = 7.2 \text{ } \mu\text{m}, E_m = 10^5 \text{ V/cm}, v_s = 10^4 \text{ cm/s} \quad (7 \text{ marks})$$

- (c) Calculate the voltage breakdown ( $V_B$ ) and maximum current density ( $J_m$ ) of a germanium lo-hi-lo diode that has the following parameters:

$$Q = 10^{10} \text{ cm}^{-2}, W_D = 10b = 15 \text{ } \mu\text{m}, E_m = 3 \times 10^5 \text{ V/cm}, v_s = 10^4 \text{ cm/s} \quad (7 \text{ marks})$$

- (d) Analyse the possible factors that produce high noise in IMPATT diodes. (5 marks)

- Q4 (a) Consider a silicon thyristor with the following parameters:

$$N_{n1} = 4 \times 10^{16} \text{ cm}^{-3}, \alpha_1 = 0.678, \alpha_2 = 0.285, n = 6$$

Calculate the avalanche breakdown voltage ( $V_B$ ), breakover voltage ( $V_{BF}$ ) and voltage ratio  $\left(\frac{V_B}{V_{BF}}\right)$  of this thyristor. (6 marks)

- (b) Consider a gallium arsenide thyristor in forward conduction mode with the following parameters:

$$N_{n1} = 4 \times 10^{16} \text{ cm}^{-3}, 2\tau_{p0} = \tau_{n0} = 10^{-3} \text{ s}, W_{n1} = 12 \text{ } \mu\text{m}, \\ W_{n2} = 5 \text{ } \mu\text{m}, A_r = 2 \times 10^{-31} \text{ cm}^6/\text{s}$$

Calculate the internal voltage drop ( $V_{int}$ ) and output current density ( $J$ ) of this thyristor. (7 marks)

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- (c) Given a silicon power MOSFET at  $T = 300\text{ K}$  has the following parameters:

$$W_{poly} = 1.2\ \mu\text{m}, W_G = 1.8\ \mu\text{m}, N_a = 10^{14}\ \text{cm}^{-3}, N_d = 10^{16}\ \text{cm}^{-3}, \\ L = 0.2\ \mu\text{m}, K_0 = 10^3, V_D = 1.5\ \text{V}, V_G = 0\ \text{V}, V_{th} = 0.2\ \text{V}, C_{ox} = 3.2\ \text{nF}$$

Determine the output resistance ( $R_0$ ) of this transistor.

(7 marks)

- (d) Analyse the function of trench structure in U-MOSFET for reducing the internal resistance of transistor.

(5 marks)

- END OF QUESTIONS -

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SEMESTER/SESSION : SEM I / 2022/2023  
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**Table 1**  
**Physical constants**

|   |  |
|---|--|
| Boltzmann's constant                    | $k = 1.38 \times 10^{-23} \text{ J/K}$<br>$= 8.62 \times 10^{-5} \text{ eV/K}$           |
| Electronic charge<br>(magnitude)        | $q = 1.6 \times 10^{-19} \text{ C}$  |
| Free electron rest mass                 | $m_0 = 9.11 \times 10^{-31} \text{ kg}$  |
| Permeability of free space              | $\mu_0 = 4\pi \times 10^{-7} \text{ H/m}$  |
| Permittivity of free space              | $\epsilon_0 = 8.85 \times 10^{-14} \text{ F/cm}$<br>$= 8.85 \times 10^{-12} \text{ F/m}$ |
| Planck's constant                       | $h = 6.625 \times 10^{-34} \text{ J-s}$<br>$= 4.135 \times 10^{-15} \text{ eV-s}$        |
| Modified Planck's constant              | $\hbar = 1.054 \times 10^{-34} \text{ J-s}$  |
| Proton rest mass                        | $M = 1.67 \times 10^{-27} \text{ kg}$  |
| Speed of light in vacuum                | $c = 2.98 \times 10^{10} \text{ cm/s}$   |
| Thermal voltage ( $T = 300 \text{ K}$ ) | $V_t = kT/q = 0.0259 \text{ V}$  |

**Table 2**  
**Work function of selected metals**

| Metal         | Work function (V) |
|---------------|-------------------|
| Silver (Ag)   | 4.26              |
| Aluminum (Al) | 4.28              |
| Gold (Au)     | 5.10              |
| Titanium (Ti) | 4.33              |
| Tungsten (W)  | 4.55              |

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## FINAL EXAMINATION

SEMESTER/SESSION : SEM I / 2022/2023

PROGRAMME CODE: BEJ

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COURSE CODE : BEJ 43303

**Table 3**  
**Silicon, Gallium Arsenide and Germanium properties ( $T = 300\text{ K}$ )**

| Property   | Si                    | GaAs                  | Ge                    |
|--|-----------------------|-----------------------|-----------------------|
| Atoms ( $\text{cm}^{-3}$ )   | $5.0 \times 10^{22}$  | $4.42 \times 10^{22}$ | $4.42 \times 10^{22}$ |
| Atomic weight  | 28.09                 | 144.63                | 72.60                 |
| Density ( $\text{g/cm}^{-3}$ )   | 2.33                  | 5.32                  | 5.33                  |
| Lattice constant ( $\text{\AA}$ )  | 5.43                  | 5.65                  | 5.65                  |
| Melting point ( $^{\circ}\text{C}$ )                                       | 1415                  | 1238                  | 937                   |
| Dielectric constant  | 11.7                  | 13.1                  | 16.0                  |
| Bandgap energy (eV)  | 1.12                  | 1.42                  | 0.66                  |
| Electron affinity, $\chi$ (volts)  | 4.01                  | 4.07                  | 4.13                  |
| Effective density of states in conduction band, $N_c$ ( $\text{cm}^{-3}$ ) | $2.8 \times 10^{19}$  | $4.7 \times 10^{17}$  | $1.04 \times 10^{19}$ |
| Effective density of states in valence band, $N_v$ ( $\text{cm}^{-3}$ )    | $1.04 \times 10^{19}$ | $7.0 \times 10^{18}$  | $6.0 \times 10^{18}$  |
| Intrinsic carrier concentration ( $\text{cm}^{-3}$ )                       | $1.5 \times 10^{10}$  | $1.8 \times 10^6$     | $2.4 \times 10^{13}$  |
| Mobility ( $\text{cm}^2/\text{V-s}$ )                                      |                       |                       |                       |
| Electron, $\mu_n$  | 1350                  | 8500                  | 3900                  |
| Hole, $\mu_p$  | 480                   | 400                   | 1900                  |
| Effective mass (density of states)   |                       |                       |                       |
| Electrons ( $\frac{m_n^*}{m_0}$ )  | 1.08                  | 0.067                 | 0.55                  |
| Holes ( $\frac{m_p^*}{m_0}$ )  | 0.56                  | 0.48                  | 0.37                  |

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FINAL EXAMINATION

SEMESTER/SESSION : SEM I / 2022/2023  
 COURSE NAME : ADVANCED SEMICONDUCTOR DEVICES

PROGRAMME CODE : BEJ  
 COURSE CODE : BEJ 43303

Table 4  
 List of formula

BJT

- |     |   |     |   |
|-----|---|-----|---|
| 1.  | $i_C = i_{E1} = \frac{eD_n A_{BE}}{x_B} \cdot n_{B0} \exp\left(\frac{qV_{BE}}{kT}\right)$   | 2.  | $i_{E2} = \frac{qD_p A_{BE}}{x_E} \cdot p_{E0} \exp\left(\frac{qV_{BE}}{kT}\right)$   |
| 3.  | $i_E = i_{E1} + i_{E2} = I_{SE} \exp\left(\frac{qV_{BE}}{kT}\right)$  | 4.  | $\frac{i_C}{i_E} = \alpha$  |
| 5.  | $\delta n_B(x) \approx \frac{n_{B0}}{x_B} \left\{ \left[ \exp\left(\frac{qV_{BE}}{kT}\right) - 1 \right] (x_B - x) - x \right\}$  | 6.  | $\delta p_E(x') \approx \frac{p_{E0}}{x_E} \left[ \exp\left(\frac{qV_{BE}}{kT}\right) - 1 \right] (x_E - x')$               |
| 7.  | $\delta p_C(x'') = -p_{C0} \cdot \exp\left(-\frac{x''}{L_C}\right)$   | 8.  | $n_B(x) = \delta n_B(x) + n_{B0}$   |
| 9.  | $p_E(x') = \delta p_E(x') + p_{E0}$   | 10. | $p_C(x'') = \delta p_C(x'') + p_{C0}$   |
| 11. | $\alpha_0 = \frac{J_C}{J_E} = \frac{J_{nC} + J_G + J_{pC0}}{J_{nE} + J_R + J_{pE}}$   | 12. | $\alpha = \frac{\partial J_C}{\partial J_E} = \frac{J_{nC}}{J_{nE} + J_R + J_{pE}}$   |
| 13. | $\alpha = \left( \frac{J_{nE}}{J_{nE} + J_{pE}} \right) \left( \frac{J_{nC}}{J_{nE}} \right) \left( \frac{J_{nE} + J_{pE}}{J_{nE} + J_R + J_{pE}} \right) = \gamma \alpha_T \delta$ | 14. | $\gamma \approx \frac{1}{1 + \frac{N_B}{N_E} \cdot \frac{D_E}{D_B} \cdot \frac{x_B}{x_E}} \quad (x_B \ll L_B, x_E \ll L_E)$ |
| 15. | $\alpha_T \approx \frac{1}{1 + \frac{1}{2} \left( \frac{x_B}{L_B} \right)^2} \quad (x_B \ll L_B)$   | 16. | $\delta = \frac{1}{1 + \frac{J_{r0}}{J_{s0}} \exp\left(-\frac{qV_{BE}}{2kT}\right)}$  |
| 17. | $n_p(0) = n_{p0} \exp\left(\frac{qV_{BE}}{kT}\right)$   | 18. | $p_p(0) = p_{p0} = N_A$   |
| 19. | $p_p(0)n_p(0) = p_{p0}n_{p0} \exp\left(\frac{qV_{BE}}{kT}\right)$   | 20. | $n'_p(0) \approx n_{p0} \exp\left(\frac{qV_{BE}}{2kT}\right)$   |

JFET

- |     |   |     |  |
|-----|---|-----|--|
| 21. | $h = \sqrt{\frac{2\epsilon_s(V_{bi} + V_{DS} - V_{GS})}{qN_d}}$   | 22. | $V_{bi} = \frac{kT}{q} \ln\left(\frac{N_a N_d}{n_i^2}\right)$  |
| 23. | $V_p = \frac{qN_D a^2}{2\epsilon_s}$  | 24. | $I_p = \frac{\mu_n (qN_d)^2 W a^3}{6\epsilon_s L}$   |
| 25. | $I_D = I_P \left[ 3 \left( \frac{V_D}{V_p} \right) - 2 \left( \frac{V_D + V_{bi} + V_G}{V_p} \right)^{3/2} + 2 \left( \frac{V_{bi} - V_G}{V_p} \right)^{3/2} \right]$ | 26. | $I_{Dsat} = I_P \left[ 1 - 3 \left( \frac{V_{bi} - V_G}{V_p} \right) \left( 1 - \frac{2}{3} \sqrt{\frac{V_{bi} - V_G}{V_p}} \right) \right]$ |
| 27. | $V_{Dsat} = V_p - (V_{bi} - V_G)$   | 28. |  |
| 29. | $g_m = \frac{3I_P}{V_p} \sqrt{\frac{V_{bi} - V_G}{V_p}} \left[ \sqrt{\frac{V_D}{V_{bi} - V_G} + 1} - 1 \right]$   | 30. | $g_{msat} = \frac{3I_P}{V_p} \left[ 1 - \sqrt{\frac{V_{bi} - V_G}{V_p}} \right]$   |

MESFET

- |     |                              |     |   |
|-----|------------------------------|-----|---|
| 31. | $R = \frac{L}{q\mu_n N_d A}$ | 32. | $V_{bi} = \phi_{Bn} - \frac{kT}{q} \ln\left(\frac{N_C}{N_d}\right)$ |
|-----|------------------------------|-----|---|

FINAL EXAMINATION

SEMESTER/SESSION : SEM I / 2022/2023  
 COURSE NAME : ADVANCED SEMICONDUCTOR DEVICES

PROGRAMME CODE : BEJ  
 COURSE CODE : BEJ 43303

Table 4  
 List of formula (Cont..)

MESFET

|     |   |     |  |
|-----|---|-----|--|
| 33. | $V_{Dsat} = \frac{qN_d a^2}{2\epsilon_s} - V_{bi} - V_G$  | 34. | $I_D = I_P \left[ \frac{V_D}{V_P} - \frac{2}{3} \left( \frac{V_D + V_G + V_{bi}}{V_P} \right)^{3/2} + \frac{2}{3} \left( \frac{V_G + V_{bi}}{V_P} \right)^{3/2} \right]$ |
| 35. | $I_P = \frac{Z\mu_n q^2 N_d^2 a^3}{2\epsilon_s L}$  | 36. | $V_P = \frac{qN_d a^2}{2\epsilon_s}$   |
| 37. | $I_{Dsat} = I_P \left[ \frac{1}{3} - \left( \frac{V_G + V_{bi}}{V_P} \right) + \frac{2}{3} \left( \frac{V_G + V_{bi}}{V_P} \right)^{3/2} \right]$ | 38. | $V_{Dsat} = V_P - V_G - V_{bi}$  |
| 39. | $g_m = \left. \frac{\partial I_D}{\partial V_G} \right _{V_D} = \frac{I_P V_D}{2V_P^2} \sqrt{\frac{V_P}{V_G + V_{bi}}} \quad (\text{linear})$     | 40. | $g_m = \frac{I_P}{V_P} \left( 1 - \sqrt{\frac{V_G + V_{bi}}{V_P}} \right) \quad (\text{saturation})$   |

MODFET

|     |  |     |   |
|-----|--|-----|---|
| 41. | $V_P = \frac{qN_d d_1^2}{2\epsilon_s}$                               | 42. | $V_T = \phi_{Bn} - \frac{\Delta E_C}{q} - V_P$                                |
| 43. | $n_s = \frac{\epsilon_{AlGaAs}(V_G - V_T)}{q(d_1 + d_0 + \Delta d)}$ | 44. | $I = \frac{Z}{L} \mu_n C_i V_D (V_G - V_T)$                                   |
| 45. | $V_{Dsat} = V_G - V_T$   | 46. | $I_{Dsat} = \frac{Z\mu_n \epsilon_s (V_G - V_T)^2}{2L(d_1 + d_0 + \Delta d)}$ |

DG MOSFET

|     |  |     |  |
|-----|--|-----|--|
| 47. | $\phi_s = \left( \frac{kT}{q} \right) \ln \left( \frac{N_a N_d}{n_i^2} \right)$  | 48. | $I_D = 2\mu_n C_{ox} \frac{W}{L} \left( V_G - V_0 - \frac{V_D}{2} \right) V_D \quad (\text{linear})$ |
| 49. | $I_D = 2\mu_n C_{ox} \frac{W}{L} \left\{ (V_G - V_0)^2 - \frac{8rk^2 T^2}{q^2} e^{q(V_G - V_0 - V_D)/kT} \right\} \quad (\text{saturation})$ |     |  |
| 50. | $I_D = \mu_n \frac{W}{L} kT n_i t_{Si} e^{(qV_G/kT)} [1 - e^{(-qV_D/kT)}] \quad (\text{subthreshold})$                                       |     |  |
| 51. | $r = \frac{\epsilon_{Si} t_{ox}}{\epsilon_{ox} t_{Si}}$  | 52. | $g_m = \mu_n \frac{8W \epsilon_{Si} kT}{Lq t_{Si}}$  |

Varactor

|     |   |     |  |
|-----|---|-----|--|
| 53. | $N = Bx^m$  | 54. | $s = \frac{1}{m+2}$  |
| 55. | $W_D = \left[ \frac{\epsilon_s (m+2)(V_R + \psi_{bi})}{qB} \right]^{\frac{1}{m+2}}$ | 56. | $C_D = \frac{\epsilon_s}{W_D} \left[ \frac{qB \epsilon_s^{m+1}}{(m+2)(V_R + \psi_{bi})} \right]^{\frac{1}{m+2}}$ |

p-i-n Diode

|     |   |     |  |
|-----|---|-----|--|
| 57. | $\tau = \frac{W}{v_s}$  | 58. | $C = \frac{\epsilon_s}{W}$   |
| 59. | $V_{BD} = E_m W$  | 60. | $J_{re} = \frac{qW n_i}{2\tau} \exp \left( \frac{qV_F}{2kT} \right)$ |
| 61. | $R_{RF} = \frac{W}{q\Delta n (\mu_n + \mu_p) A} = \frac{W^2}{J_F \tau (\mu_n + \mu_p) A}$ | 62. | $J_F = \frac{qW \Delta n}{\tau}$                                     |



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SEMESTER/SESSION : SEM I / 2022/2023  
 COURSE NAME : ADVANCED SEMICONDUCTOR DEVICES

PROGRAMME CODE : BEJ  
 COURSE CODE : BEJ 43303

Table 4  
 List of formula (Cont..)

IMPATT Diode

|     |  |     |  |
|-----|--|-----|--|
| 63. | $V_B = \frac{1}{2} E_m W_D = \frac{\epsilon_s E_m^2}{2qN} (1 - sided)$               | 64. | $V_B = \frac{1}{2} E_m W_D = \frac{\epsilon_s E_m^2}{qN} (2 - sided)$      |
| 65. | $V_B = E_m W_D = -\frac{qN_1 b}{\epsilon_s} \left( W_D - \frac{b}{2} \right) (Read)$ | 66. | $V_B = \frac{E_m b}{2} + \frac{qN_2 W_D (W_D - b)}{2\epsilon_s} (Hi - Lo)$ |
| 67. | $V_B = E_m b + \left( E_m - \frac{qQ}{\epsilon_s} \right) (W_D - b) (Lo - Hi - Lo)$  | 68. | $V_m = E_m W_D$  |
| 69. | $J_m = \frac{E_m \epsilon_s v_s}{W_D}$   | 70. | $P_m = E_m^2 \epsilon_s v_s$   |

Thyristors

|     |  |     |  |
|-----|--|-----|--|
| 71. | $V_B \approx 6 \times 10^{13} (N_{n1})^{-0.75}$                                    | 72. | $V_{PT} = \frac{qN_{n1} W_{n1}^2}{2\epsilon_s}$                        |
| 73. | $V_{BR} = V_B (1 - \alpha_1)^{\frac{1}{n}}$  | 74. | $\alpha_1 = \text{sech} \left( \frac{W}{L_{n1}} \right)$               |
| 75. | $W = W_{n1} \left( 1 - \sqrt{\frac{V_{AK}}{V_{PT}}} \right)$                       | 76. | $I_{C1} = \alpha I_E + I_{CO1}$  |
| 77. | $I_{B1} = (1 - \alpha_1) I_A - I_{CO1}$  | 78. | $I_{C2} = \alpha_2 I_K + I_{CO2}$                                      |
| 79. | $I_A = \frac{\alpha_2 I_g + I_{CO1} + I_{CO2}}{1 - (\alpha_1 + \alpha_2)}$         | 80. | $V_{BF} = V_B (1 - \alpha_1 - \alpha_2)^{1/n}$                         |
| 81. | $V_{AK} = V_1 -  V_2  + V_3$   | 82. | $J = \frac{qnW_i}{\tau_{eff}}$   |
| 83. | $\tau_{eff} = \frac{1}{\left( 2A_r n^2 + \frac{1}{\tau_{p0} + \tau_{n0}} \right)}$ | 84. | $V_{int} = \frac{W_{n1} + W_{p2}}{(\mu_n + \mu_p) \tau_{eff}}$         |
| 85. | $J = \frac{4qn_i D_a F_L}{W_{n1} + W_{p2}} e^{\frac{V_{AK}}{2kT}}$                 | 86. | $J_{re} = \frac{qn_i D_a}{2(W_{n1} + W_{p2})} e^{\frac{qV_{AK}}{2kt}}$ |
| 87. | $F_L = \frac{W_{n1} + W_{p2}}{\sqrt{D_a (\tau_p + \tau_n)}}$                       | 88. | $D_a = \frac{2D_n D_p}{D_n + D_p}$                                     |

Power MOSFET

|     |  |     |   |
|-----|--|-----|---|
| 89. | $R_{on} = \frac{4V_B^2}{\epsilon_s \mu_n E^3}$   | 90. | $t = \sqrt{\frac{2\epsilon_s V_B}{qN_d}}$   |
| 91. | $I_D = \frac{Z \mu_n C_{ox} [(V_G - V_{Th}) V_D]}{L}$  | 92. | $I_{Dsat} = \frac{Z \mu_n C_{ox} (V_G - V_{Th})^2}{L - \Delta L}$                       |
| 93. | $\Delta L = K_0 \sqrt{\frac{2\epsilon_s V_D}{q} \left[ \frac{N_d}{N_a (N_a + N_d)} \right]}$ | 94. | $g_m = \frac{\Delta I_D}{\Delta V_G} = \frac{2\mu_n C_{ox} (V_G - V_{Th})}{L W_{cell}}$ |

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 COURSE NAME : ADVANCED SEMICONDUCTOR DEVICES

PROGRAMME CODE : BEJ  
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**Table 4**  
**List of formula (Cont..)**

**Power MOSFET**

|     |   |      |  |
|-----|---|------|--|
| 95. | $W_{cell} = W_G + W_{poly}$                                 | 96.  | $R_0 = \frac{W_{cell} b \sqrt{V_D}}{\mu_n C_{ox} (V_G - V_{Th})^2} \left( \frac{L}{b} - V_D \right)^2$ |
| 97. | $R_{ch} = \frac{L W_{cell}}{2 \mu_n C_{ox} (V_G - V_{Th})}$ | 98.  | $b = K_0 \sqrt{\frac{2 \epsilon_s}{q} \left[ \frac{N_d}{N_a (N_a + N_d)} \right]}$                     |
| 99. | $C_{ox} = \frac{\epsilon_{ox}}{t_{ox}}$                     | 100. | $C_{IN} = \frac{2 x_{PL} \epsilon_{ox}}{W_{cell} t_{ox}} + \frac{W_G \epsilon_{ox}}{W_{cell} t_{Eox}}$ |

**BJT (Nonideal Effects)**

|      |  |      |   |
|------|--|------|---|
| 101. | $n_{iE} = n_i \sqrt{e^{\left( \frac{\Delta E_g}{kT} \right)}}$                               | 102. | $\gamma = \frac{1}{1 + \frac{p_{E0} D_E L_B}{n_{B0} D_B L_E} \times \frac{\tanh\left(\frac{x_B}{L_B}\right)}{\tanh\left(\frac{x_E}{L_E}\right)}}$ |
| 103. | $p_{E0} = \frac{n_{iE}^2}{N_E} = \frac{n_i^2}{N_E} e^{\left( \frac{\Delta E_g}{kT} \right)}$ | 104. | $E = \frac{kT}{q} \frac{1}{N_a} \frac{dN_a}{dx}$  |

**JFET (Nonideal Effects)**

|      |  |      |   |
|------|--|------|---|
| 105. | $I'_p = \frac{\mu_n (q N_d)^2 W a^3}{6 \epsilon_s \left( L - \frac{\Delta L}{2} \right)}$          | 106. | $\Delta L = \sqrt{\frac{2 \epsilon_s (V_D - V_{Dsat})}{q N_d}}$             |
| 107. | $I'_D = I_D \left( \frac{I'_p}{I_p} \right) = I_D \left( \frac{L}{L - \frac{\Delta L}{2}} \right)$ | 108. | $r_d = \frac{\partial V_D}{\partial I'_D} = \frac{\Delta V_D}{\Delta I'_D}$ |
| 109. | $I'_{Dsat} = q N_d v_{sat} (a - h_{sat}) W$  |      |   |